

E3M0065090D

Silicon Carbide Power MOSFET E-Series Automotive

N-Channel Enhancement Mode

Features

- 3rd generation SiC MOSFET technology
- High blocking voltage with low On-resistance
- High speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery (Qrr)
- Halogen free, RoHS compliant
- Automotive Qualified (AEC-Q101) and PPAP Capable

Benefits

- Higher system efficiency
- Reduced cooling requirements
- Increased power density
- Increased system switching frequency

Applications

- Renewable energy
- EV battery chargers
- High voltage DC/DC converters
- Switch Mode Power Supplies

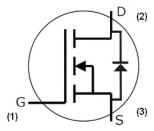


Package









Part Number	Package	Marking
E3M0065090D	T0-247-3	E3M0065090

Maximum Ratings (T_c = 25 °C unless otherwise specified)

Symbol	Parameter		Unit	Test Conditions	Note
V _{DSmax}	Drain - Source Voltage	900	٧	V _{GS} = 0 V, I _D = 100 μA	
V _{GSmax}	Gate - Source Voltage		٧		Note: 1
V_{GSop}	Gate - Source Voltage (Recommended operating values)		٧		Note: 2
	Continuous Drain Current	35	А	V _{GS} = 15 V, T _C = 25°C	Fig. 19
I _D	Continuous Drain Current	23	A	V _{GS} = 15 V, T _C = 100°C	
I _{D(pulse)}	Pulsed Drain Current	90	А	Pulse width t _P limited by T _{jmax}	Fig. 22
P _D	Power Dissipation	125	W	$T_{c}=25^{\circ}C, T_{J}=150^{\circ}C$	Fig. 20
T_J , T_{stg}	Operating Junction and Storage Temperature	-55 to +150	°C		
T _L	Solder Temperature	260	°C	1.6mm (0.063") from case for 10s	
M _d	Mounting Torque	1 8.8	Nm lbf-in	M3 or 6-32 screw	

Note (1): When using MOSFET Body Diode V $_{\rm GSmax}$ = -4V/+18V Note (2): MOSFET can also safely operate at 0/+15 V



Symbol	Parameter	Min.	Тур.	Max.	Unit	Test Conditions	Note	
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	900			V	V _{GS} = 0 V, I _D = 100 μA		
V Coto Throughold Voltage	1.7	2.1	3.5	٧	V _{DS} = V _{GS} , I _D = 5 mA	Fig. 11		
V GS(th)	V _{GS(th)} Gate Threshold Voltage		1.6		V		V _{DS} = V _{GS} , I _D = 5 mA, T _J = 150°C	
I _{DSS}	Zero Gate Voltage Drain Current		1	100	μΑ	V _{DS} = 900 V, V _{GS} = 0 V		
I_{GSS}	Gate-Source Leakage Current		10	250	nA	V _{GS} = 15 V, V _{DS} = 0 V		
D	Drain-Source On-State Resistance		65	84.5	mΩ	$V_{GS} = 15 \text{ V, } I_D = 20 \text{ A}$	Fig. 4,	
$R_{DS(on)}$	Diam-Source off-State Resistance		90		111122	$V_{GS} = 15 \text{ V, } I_D = 20 \text{A, } T_J = 150 ^{\circ}\text{C}$	5, 6	
\mathbf{g}_{fs}	Transconductance		13.6		S	V _{DS} = 20 V, I _{DS} = 20 A	Fig. 7	
yts .	Transconductance		11.6		3	V _{DS} = 20 V, I _{DS} = 20 A, T _J = 150°C		
C _{iss}	Input Capacitance		660				Fig. 17, 18	
Coss	Output Capacitance		60		pF	V _{GS} = 0 V, V _{DS} = 600 V		
C_{rss}	Reverse Transfer Capacitance		4.0			f = 1 MHz - V _{AC} = 25 mV		
E _{oss}	C _{oss} Stored Energy		16		μJ	VAC - 25 IIIV		
Eon	Turn-On Switching Energy (Body Diode FWD)		226			$V_{DS} = 400 \text{ V}, V_{GS} = -4 \text{ V}/15 \text{ V}, I_{D} = 20 \text{A},$	Fig. 26, Note 3	
E _{OFF}	Turn Off Switching Energy (Body Diode FWD)		36		μJ	$R_{G(ext)} = 2.5\Omega$, L= 77 μ H, $T_J = 150$ °C		
t _{d(on)}	Turn-On Delay Time		35					
t _r	Rise Time		11		$V_{DD} = 400 \text{ V}, V_{GS} = -4 \text{ V}/15 \text{ V}$ $I_D = 20 \text{ A}, R_{G(ext)} = 2.5 \Omega,$			
t _{d(off)}	Turn-Off Delay Time		23		ns	Timing relative to V _{DS}	Fig. 27	
t _f	Fall Time		9		1	inductive load		
R _{G(int)}	Internal Gate Resistance		4.7		Ω	f = 1 MHz, V _{AC} = 25 mV		
Q_{gs}	Gate to Source Charge		7.5		V _{DS} = 400 V, V _{GS} = -4 V/15 V nC I _D = 20 A		Fig. 12	
Q_{gd}	Gate to Drain Charge		12]				
Qg	Total Gate Charge		30.4]		Per IEC60747-8-4 pg 21		

Reverse Diode Characteristics ($T_c = 25^{\circ}C$ unless otherwise specified)

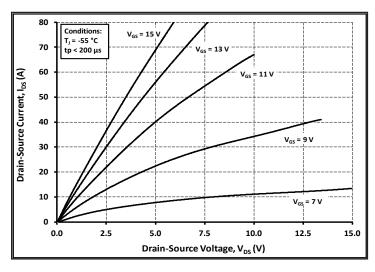
Symbol	Parameter	Тур.	Max.	Unit	Test Conditions	Note	
$V_{ ext{SD}}$	Diode Forward Voltage	4.8		٧	V _{GS} = -4 V, I _{SD} = 10 A	Fig. 8, 9, 10	
		4.4		٧	V _{GS} = -4 V, I _{SD} = 10 A, T _J = 150 °C		
Is	Continuous Diode Forward Current		23.5	Α	V _{GS} = -4 V, T _C = 25°C	Note 1	
I _{S, pulse}	Diode pulse Current		90	Α	V _{GS} = -4 V, pulse width t _P limited by T _{jmax}	Note 1	
t _{rr}	Reverse Recover time	35		ns			
Q _{rr}	Reverse Recovery Charge	150		nC	V _{es} = -4 V, I _{sp} = 20 A, V _R = 400 V dif/dt = 950 A/µs, T _J = 150 °C	Note 1	
I _{rrm}	Peak Reverse Recovery Current	5.6		А	-		

Thermal Characteristics

Symbol	Parameter	Max.	Unit	Test Conditions	Note
R _θ JC	Thermal Resistance from Junction to Case	1.0	80.04		Fi. 01
$R_{\theta JA}$	Thermal Resistance From Junction to Ambient	40	°C/W		Fig. 21

Note (3): Turn-off and Turn-on switching energy and timing values measured using SiC MOSFET Body Diode





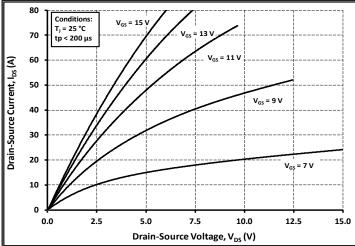
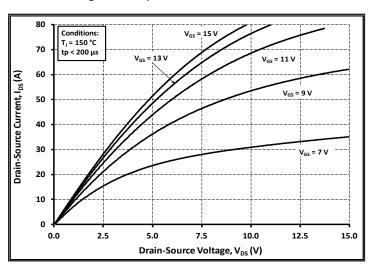


Figure 1. Output Characteristics T_J = -55 °C





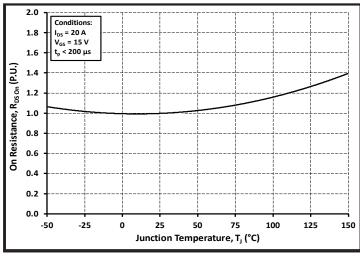
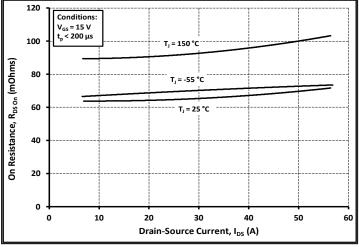


Figure 3. Output Characteristics T_J = 150 °C

Figure 4. Normalized On-Resistance vs. Temperature



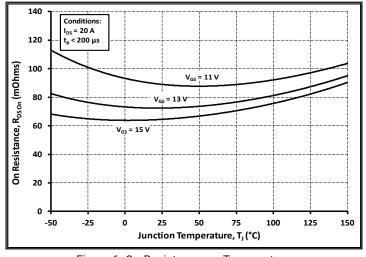
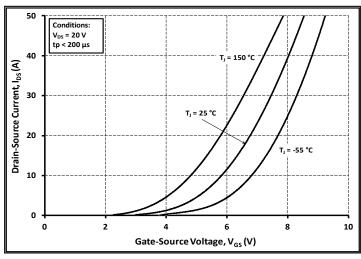


Figure 5. On-Resistance vs. Drain Current For Various Temperatures

Figure 6. On-Resistance vs. Temperature For Various Gate Voltage





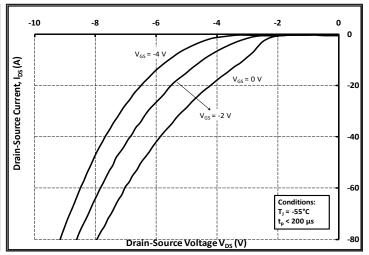
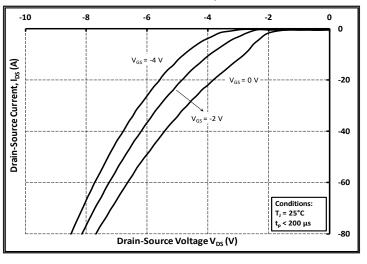


Figure 7. Transfer Characteristic for Various Junction Temperatures

Figure 8. Body Diode Characteristic at -55 °C



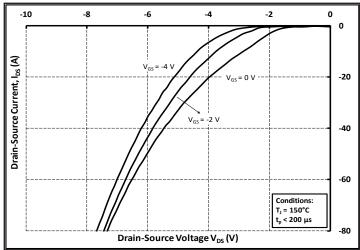
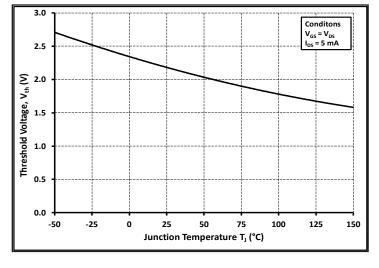


Figure 9. Body Diode Characteristic at 25 °C

Figure 10. Body Diode Characteristic at 150 °C



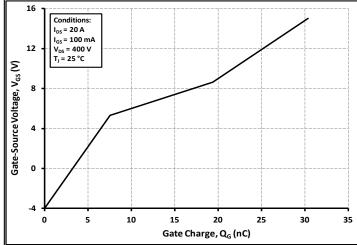


Figure 11. Threshold Voltage vs. Temperature

Figure 12. Gate Charge Characteristics



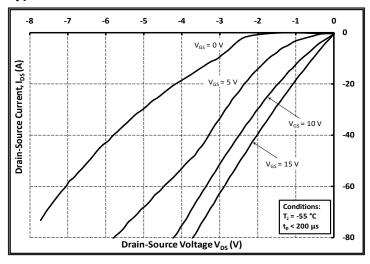
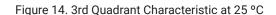
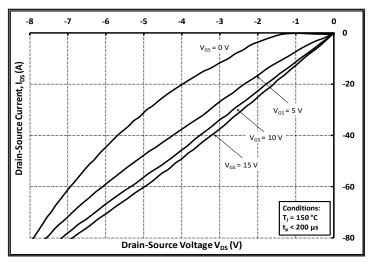


Figure 13. 3rd Quadrant Characteristic at -55 °C





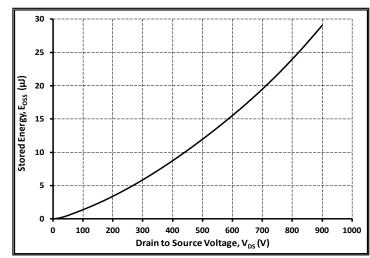
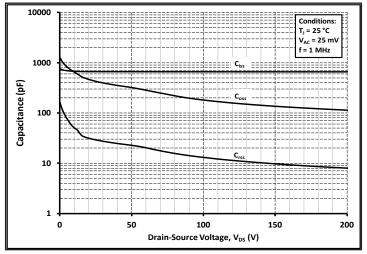


Figure 15. 3rd Quadrant Characteristic at 150 °C

Figure 16. Output Capacitor Stored Energy



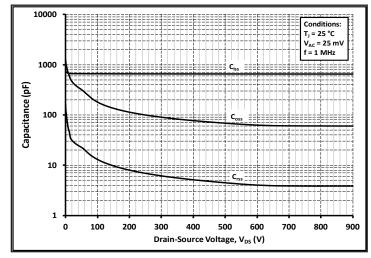


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200V)

Figure 18. Capacitances vs. Drain-Source Voltage (0 - 900V)



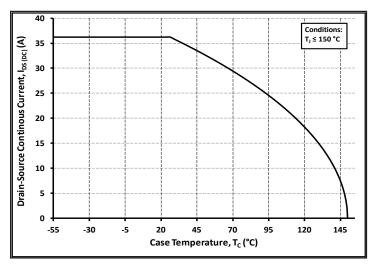


Figure 19. Continuous Drain Current Derating vs. Case Temperature

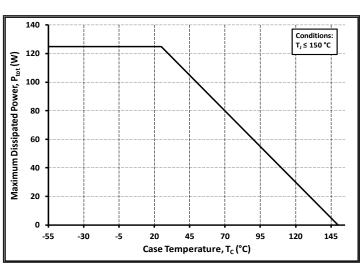


Figure 20. Maximum Power Dissipation Derating vs.

Case Temperature

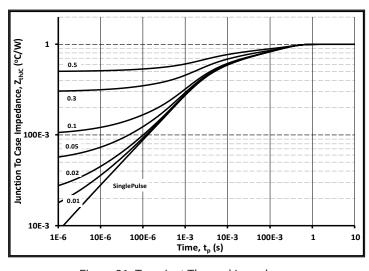


Figure 21. Transient Thermal Impedance (Junction - Case)

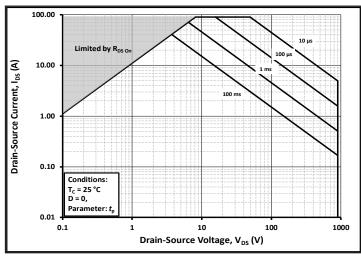


Figure 22. Safe Operating Area

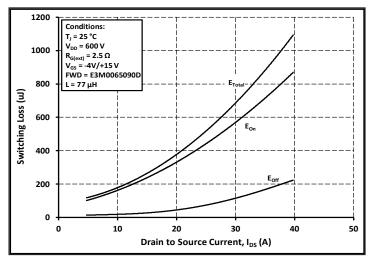


Figure 23. Clamped Inductive Switching Energy vs. Drain Current ($V_{DD} = 600V$)

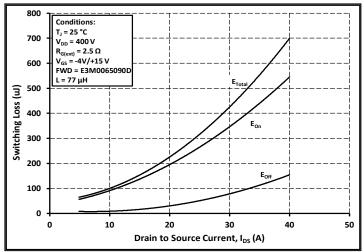


Figure 24. Clamped Inductive Switching Energy vs. Drain Current (V_{DD} = 400V)



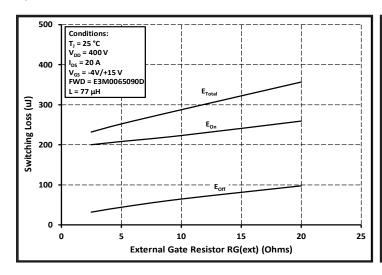


Figure 25. Clamped Inductive Switching Energy vs. $R_{G(ext)}$

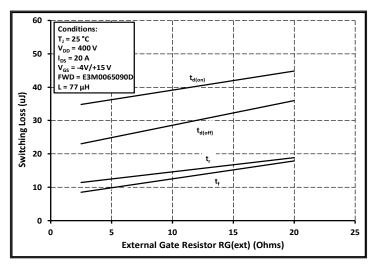


Figure 27. Switching Times vs. R_{G(ext)}

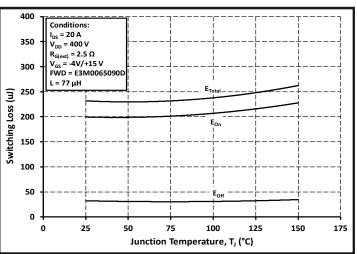


Figure 26. Clamped Inductive Switching Energy vs.
Temperature

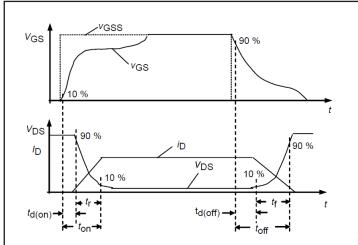


Figure 28. Switching Times Definition



Test Circuit Schematic

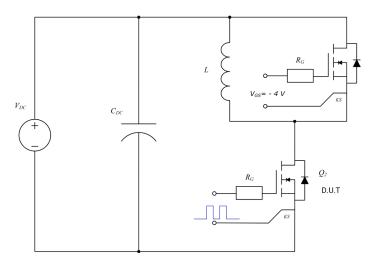


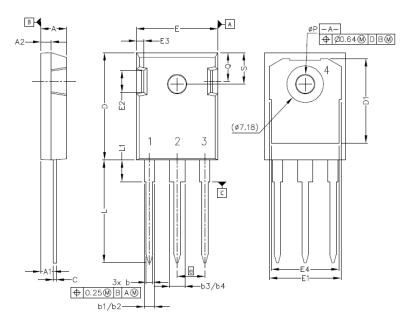
Figure 29. Clamped Inductive Switching Waveform Test Circuit

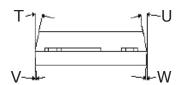
Note (3): Turn-off and Turn-on switching energy and timing values measured using SiC MOSFET Body Diode as shown above.



Package Dimensions

Package TO-247-3



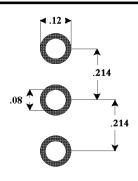


Pinout Information:

- Pin 1 = Gate Pin 2, 4 = Drain
- Pin 3 = Source

noc	Inc	hes	Millimeters		
POS	Min	Max	Min	Max	
А	.190	.205	4.83	5.21	
A1	.090	.100	2.29	2.54	
A2	.075	.085	1.91	2.16	
b	.042	.052	1.07	1.33	
b1	.075	.095	1.91	2.41	
b2	.075	.085	1.91	2.16	
b3	.113	.133	2.87	3.38	
b4	.113	.123	2.87	3.13	
С	.022	.027	0.55	0.68	
D	.819	.831	20.80	21.10	
D1	.640	.695	16.25	17.65	
D2	.037	.049	0.95	1.25	
Е	.620	.635	15.75	16.13	
E1	.516	.557	13.10	14.15	
E2	.145	.201	3.68	5.10	
E3	.039	.075	1.00	1.90	
E4	.487	.529	12.38 13.43		
е	.214	BSC	5.44 BSC		
N	3	3	3		
L	.780	.800	19.81	20.32	
L1	.161	.173	4.10	4.40	
ØP	.138	.144	3.51	3.65	
Q	.216	.236	5.49	6.00	
S	.238	.248	6.04	6.30	
Т	9°	11°	9°	11°	
U	9°	11°	9°	11°	
V	2°	8°	2°	8°	
W	2°	8°	2°	8°	

Recommended Solder Pad Layout





Notes

RoHS Compliance

The levels of RoHS restricted materials in this product are below the maximum concentration values (also referred to as the threshold limits) permitted for such substances, or are used in an exempted application, in accordance with EU Directive 2011/65/EC (RoHS2), as implemented January 2, 2013. RoHS Declarations for this product can be obtained from your Cree representative or from the Product Documentation sections of www.cree.com.

REACh Compliance

REACh substances of high concern (SVHCs) information is available for this product. Since the European Chemical Agency (ECHA) has published notice of their intent to frequently revise the SVHC listing for the foreseeable future, please contact a Cree representative to insure you get the most up-to-date REACh SVHC Declaration. REACh banned substance information (REACh Article 67) is also available upon request.

This product has not been designed or tested for use in, and is not intended for use in, applications implanted into the human body
nor in applications in which failure of the product could lead to death, personal injury or property damage, including but not limited
to equipment used in the operation of nuclear facilities, life-support machines, cardiac defibrillators or similar emergency medical
equipment, aircraft navigation or communication or control systems, air traffic control systems.

Related Links

- SPICE Models: http://wolfspeed.com/power/tools-and-support
- SiC MOSFET Isolated Gate Driver reference design: http://wolfspeed.com/power/tools-and-support
- SiC MOSFET Evaluation Board: http://wolfspeed.com/power/tools-and-support